## Application/Control No. Applicant(s)/Patent Under Reexamination 10/560,752 BEN-AYUN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 LEE NGUYEN 2618 U.S. PATENT DOCUMENTS **Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-5,894,496 04-1999 Jones, Mark Alan 455/126 Α \* US-5,623,226 04-1997 Whitmarsh et al. 330/2 В \* US-2007/0184789 08-2007 Ben-Ayun et al. 455/126 С D US-US-Ε US-F US-G US-Н US-1 US-US-US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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